

What is claimed is:

1. A data storage device comprising:
 storage means, installed in a housing, for storing predetermined confidential data;
 data generation means for generating data representing deflection of said housing in which said storage means is installed; and
 detection means for detecting physical impact applied to said housing in accordance with the data generated by said data generation means.
2. A data storage device comprising:
 storage means, installed in a housing, for storing predetermined confidential data;
 data generation means for generating data representing deflection of said housing in which said storage means is installed;
 detection means for detecting physical impact applied to said housing by specifying the deflection of said housing in accordance with the data generated by said data generation means; and
 data cancel means for canceling the confidential data stored in said storage means when said detection means detects physical impact applied to said housing.
3. The data storage device according to claim 1, further comprising:
 measure means for measuring temperature in said housing in which said storage means is installed; and
 correction means for correcting the data generated by said data generation means in accordance with the temperature measured by said measure means, wherein said detection means detects the physical impact applied to said housing in accordance with the data representing the deflection after the correction by said correction means.

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correction means for correcting the data generated by said data generation

5. A data storage device comprising:

a plurality of electrodes, arranged in said housing in which said memory is

a detection processor for detecting physical impact applied to said housing in accordance with shift degrees of the capacitance at said electrodes.

6. A data storage device comprising:

a memory, installed in a tight housing having predetermined shape, which stores predetermined confidential data;

a plurality of electrodes, arranged in said housing in which said memory is

5 installed, which generates predetermined capacitance;

a detection processor which specifies deflection of said housing in accordance with shift degrees of the capacitance at said electrodes to detect physical impact applied to said housing; and

10 a data canceler which cancels the confidential data stored in said memory
when said detection processor detects the physical impact applied to said
housing.

7. The data storage device according to claim 5, further comprising:

5 said electrodes in accordance with the temperature measured by said thermo-
sensor,

[illegible]

a thermo-sensor which measures temperature in said housing in which said memory is installed; and

wherein said detection processor detects the physical impact applied to said housing in accordance with the deflection of said housing after the correction by said correction processor.

generating data representing deflection of a housing in which a storage device for storing predetermined confidential data is installed; and

10. A detection method comprising:

measuring temperature in said housing in which said storage device is
5 installed;

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10 housing after correction by said correcting data.

measuring capacitance at a plurality of electrodes arranged in a tight housing
in which a memory for storing predetermined confidential data is installed; and
detecting physical impact applied to said housing in accordance with shift
5 degrees of the capacitance measured by said measuring capacitance.

measuring capacitance at a plurality of electrodes arranged in a housing in which a memory for storing predetermined confidential data is installed;

measuring temperature in said housing in which said memory is installed;

5 correcting the capacitance measured by said measuring capacitance in accordance with the temperature measured by said measuring temperature; and

detecting physical impact applied to said housing by specifying deflection of said housing in accordance with shift degrees of the capacitance after the correction by said correcting the capacitance.